

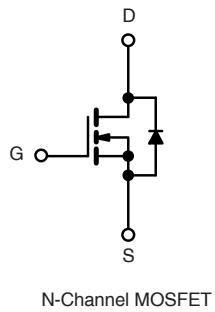
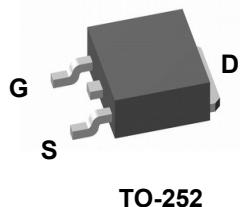
N-Channel PowerTrench[®] MOSFET

100V,15A,114mΩ

Features

$R_{DS(ON)} = 114 \text{ m}\Omega @ V_{GS} = 10\text{V}$

$R_{DS(ON)} = 120\text{m}\Omega @ V_{GS} = 4.5\text{V}$



ABSOLUTE MAXIMUM RATINGS $(T_A = 25^\circ\text{C}, \text{unless otherwise noted})$			
Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V_{DS}	100	V
Gate-Source Voltage	V_{GS}	± 20	
Continuous Drain Current ($T_J = 175^\circ\text{C}$) ^b	I_D	15	A
$T_C = 125^\circ\text{C}$		13	
Pulsed Drain Current	I_{DM}	40	A
Continuous Source Current (Diode Conduction)	I_S	3	
Avalanche Current	I_{AS}	3	
Single Pulse Avalanche Energy	E_{AS}	18	mJ
Maximum Power Dissipation	P_D	96 ^b	W
$T_A = 25^\circ\text{C}$		3 ^a	
Operating Junction and Storage Temperature Range	T_J, T_{stg}	- 55 to 175	°C

THERMAL RESISTANCE RATINGS				
Parameter	Symbol	Typical	Maximum	Unit
Junction-to-Ambient ^a	R_{thJA}	15	18	°C/W
Steady State		40	50	
Junction-to-Case (Drain)	R_{thJC}	0.85	1.1	

Notes:

a. Surface mounted on 1" x 1" FR4 board.

b. See SOA curve for voltage derating.

SPECIFICATIONS ($T_J = 25^\circ\text{C}$, unless otherwise noted)

Parameter	Symbol	Test Conditions Min.		Typ. ^a	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100			V
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	1.0		2.5	
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
		$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 125^\circ\text{C}$			50	
		$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 175^\circ\text{C}$			250	
On-State Drain Current ^b	$I_{D(\text{on})}$	$V_{DS} = 5 \text{ V}, V_{GS} = 10 \text{ V}$	40			A
Drain-Source On-State Resistance ^b	$R_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}, I_D = 3 \text{ A}$		0.114		Ω
		$V_{GS} = 10 \text{ V}, I_D = 3 \text{ A}, T_J = 125^\circ\text{C}$		0.120		
		$V_{GS} = 10 \text{ V}, I_D = 3 \text{ A}, T_J = 175^\circ\text{C}$		0.140		
		$V_{GS} = 4.5 \text{ V}, I_D = 3 \text{ A}$		0.120		
Forward Transconductance ^b	g_{fs}	$V_{DS} = 15 \text{ V}, I_D = 3 \text{ A}$		35		S
Dynamic^a						
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, F = 1 \text{ MHz}$		950		pF
Output Capacitance	C_{oss}			120		
Reverse Transfer Capacitance	C_{rss}			60		
Total Gate Charge ^c	Q_g	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 3 \text{ A}$		24	41	nC
Gate-Source Charge ^c	Q_{gs}			8		
Gate-Drain Charge ^c	Q_{gd}			12		
Gate Resistance	R_g	$V_{DD} = 50 \text{ V}, R_L = 5.2 \Omega$ $I_D = 3 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 2.5 \Omega$	0.5		2.9	Ω
Turn-On Delay Time ^c	$t_{d(\text{on})}$			15	25	ns
Rise Time ^c	t_r			50	75	
Turn-Off Delay Time ^c	$t_{d(\text{off})}$			30	45	
Fall Time ^c	t_f			60	90	
Source-Drain Diode Ratings and Characteristics ($T_C = 25^\circ\text{C}$)						
Pulsed Current	I_{SM}				5	A
Diode Forward Voltage ^b	V_{SD}	$I_F = 3 \text{ A}, V_{GS} = 0 \text{ V}$		0.9	1.5	V
Source-Drain Reverse Recovery Time	t_{rr}	$I_F = 3 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}$		180	250	ns

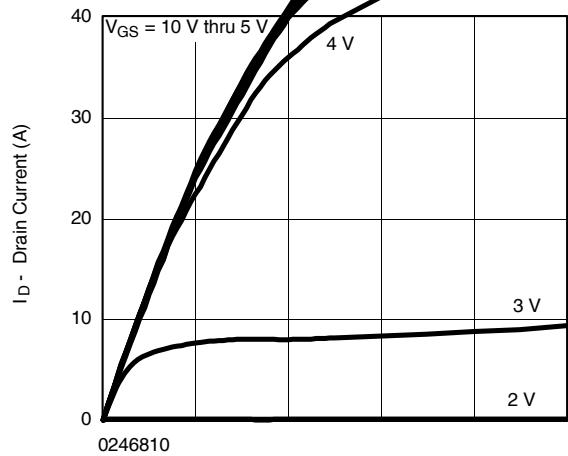
Notes:

a. Guaranteed by design, not subject to production testing.

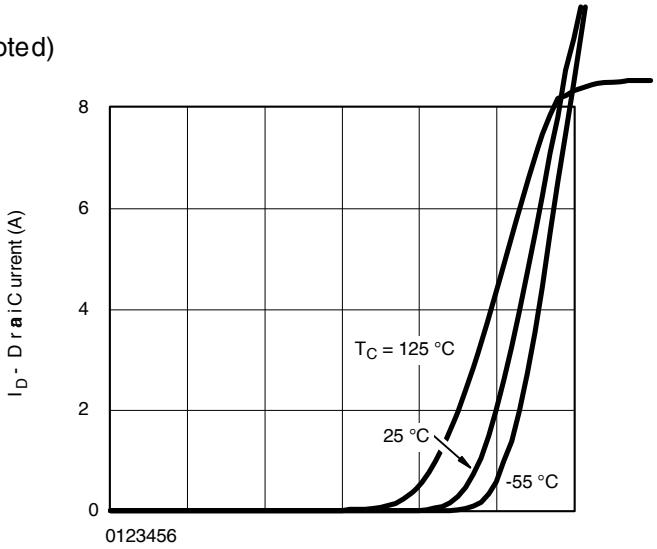
b. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.

c. Independent of operating temperature.

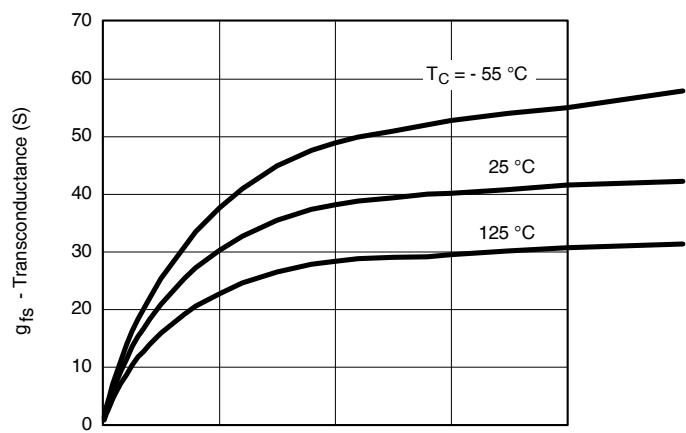
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



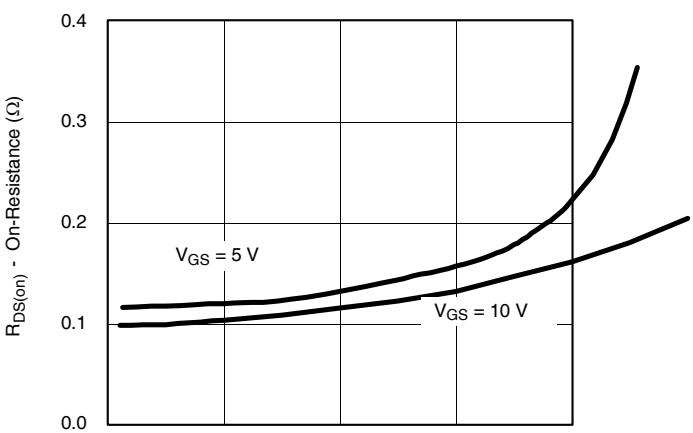
Output Characteristics



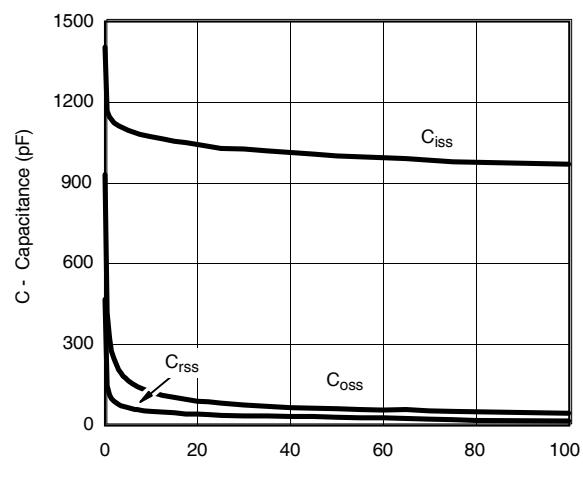
Transfer Characteristics



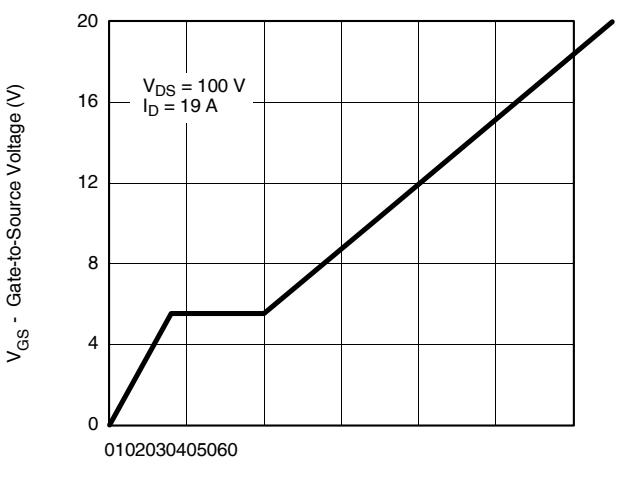
Transconductance



On-Resistance vs. Drain Current

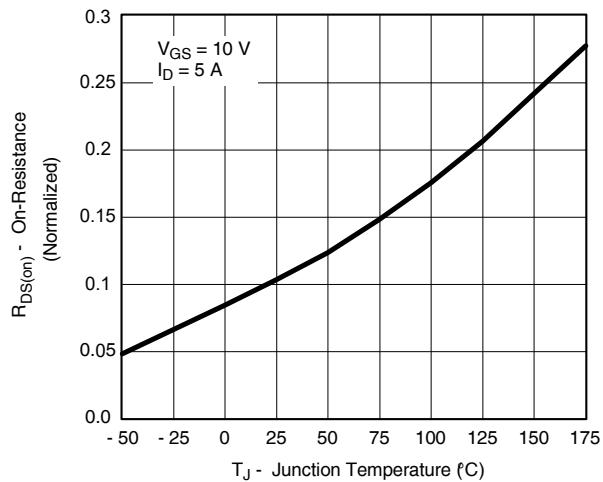


Capacitance

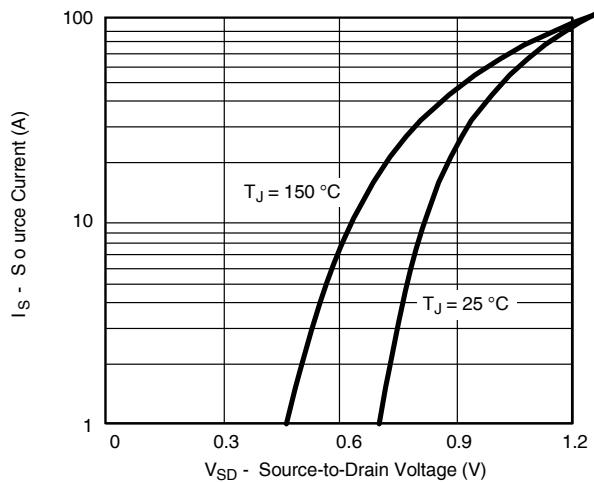


Gate Charge

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

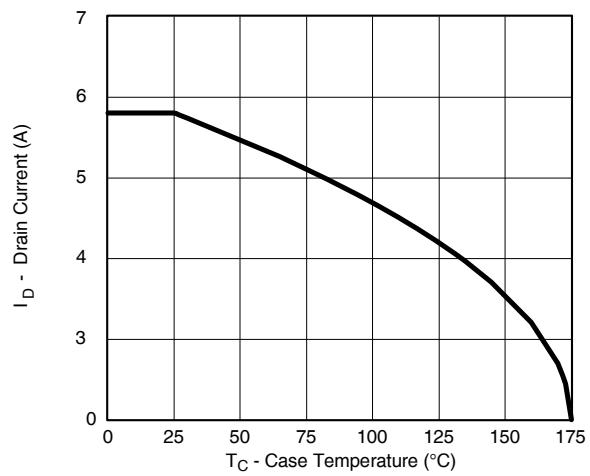


On-Resistance vs. Junction Temperature

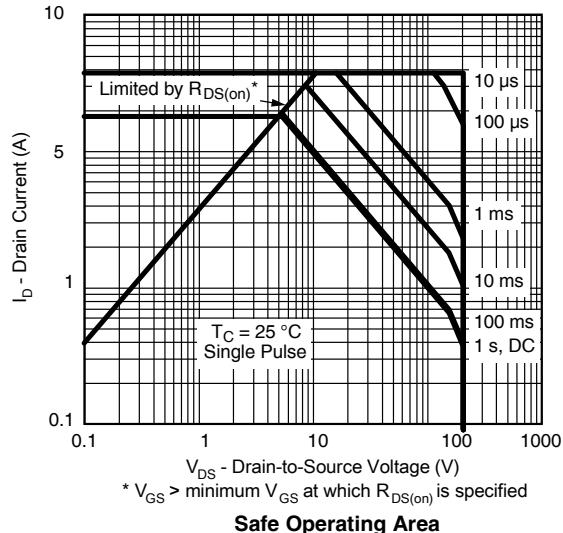


Source-Drain Diode Forward Voltage

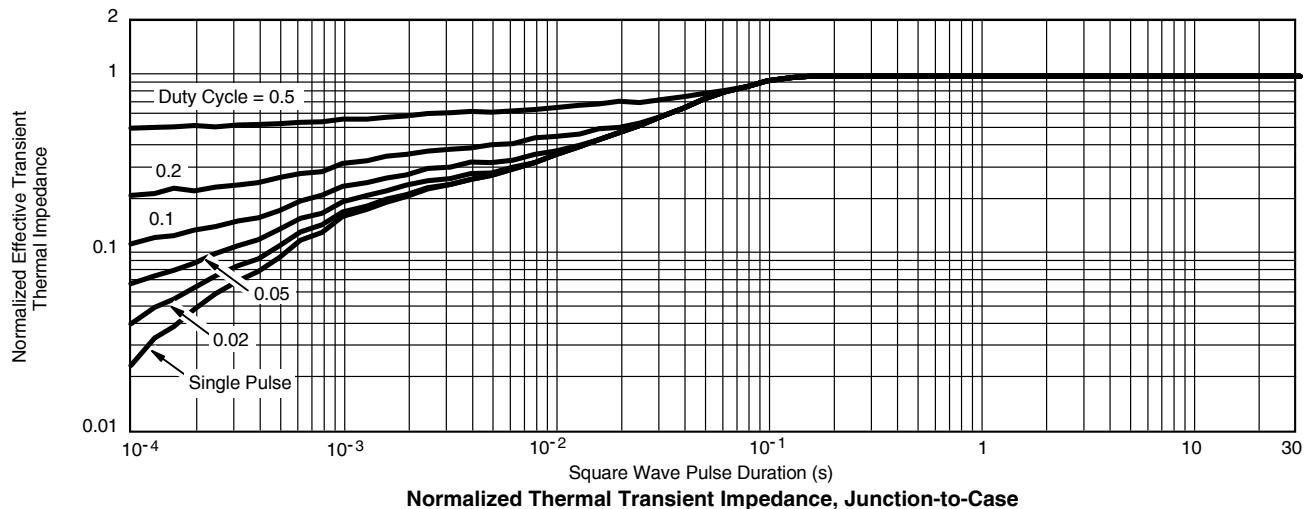
THERMAL RATINGS



Maximum Avalanche Drain Current
vs. Case Temperature



Safe Operating Area



Normalized Thermal Transient Impedance, Junction-to-Case